

Based on Form PTO-1449 (3/90) LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. 455610-2580.1	SERIAL NO. 10/673,712
	APPLICANT Lawrence SALANT et al.	
	FILING DATE September 29, 2003	GROUP 2117

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	AA	6 407 970	06/2002	Verboom, Johannes J.			
	AB	6 853 696	02/2005	Moser et al.			
	AC	4 615 040	09/1986	Mojoli et al.			
	AD	6 812 688	11/2004	Tan et al.			
	AE	2001 0021151	09/2001	Verboom, Johannes et al.			
	AF	6 463 109 B1	10/2002	McCormack et al.			
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	AH	2004 0123018 A1	06/2004	Miller et al.			
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	AK	4 633 465	12/30/86	Fitch et al.			
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	AO	5,825,825	10/20/98	Altmann et al			
	AP	5,900,755	05/04/99	Toeppen et al			
	AQ	6,215,363	04/10/01	Conta et al			
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	AS	6,445,230	09/03/02	Rupp et al			

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	AY	5,914,592	06/22/99	Saito			
	AZ	5,789,954	08/04/98	Toeppen et al			
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	BF	5,432,791	07/11/95	Gancarcik			
	BG	6,539,318	03/25/03	Miller et al.			
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	BI	4,758,963	07/19/88	Gordon et al.			
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	BK	6,571,186	05/27/03	Ward			
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	BN	5,714,878	02/03/98	Saito et al.			

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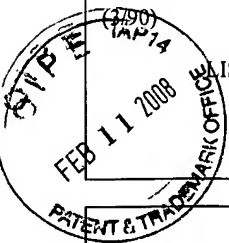
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	BS	5,978,742	11/02/99	Pirkerd			
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	BU	5,953,071	09/14/99	Van Zon			
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	CF	6,278,357	08/21/01	Croushore et al.			
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	CT	5 305 635 A	04/1994	James et al.			

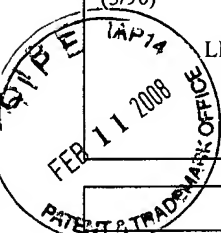
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	CU	JP4105070	04/07/92	Japan			Abstract
	CV	JP5196641	08/06/93	Japan			Abstract
	CW	JP5264595	10/12/93	Japan			Abstract
	CX	JP8220144	06/22/99	Japan			Abstract
	CY	JP9005362	01/10/97	Japan			Abstract
	CZ	JP10163859	06/19/98	Japan			Abstract
	DA	JP11098876	04/09/99	Japan			Abstract
	DB	JP62003544	01/09/87	Japan			Abstract
	DC	EP 0 631 143	12/28/94	Europe			
	DD	EP 0 241 142	10/14/87	Europe			

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	DI	EP 1 244 241	09/25/02	Europe			
	DJ	EP 1 074 845	02/07/01	Europe			
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	DO	Roland E. Best, <i>The Software PLL, Phase Locked Loops</i> , 3 rd Edition, McGraw-Hill, New York, 1997, pp 229-249
	DP	<i>Using FPGAs for Digital Applications</i> , Actel Corporation, April 1996
	DQ	HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999
	DR	Infiniium DCA, Agilent Technologies, March 7, 2002
	DS	Communication waveform measurements, Hewlett Packard, June 26, 1996
	DT	Advanced Analysis of High-Speed Digital Communication Waveforms, Hewlett Packard, June 27, 1994
	DU	R.E. Anderson and E. M. Foster, Design of an MPEG-2 Transport Demultiplexor Core, IBM, 1999
	DV	Technology Standards, Tektronix Website (www.tek.com/Masurement/Solutions/tech_standards/index.html?wt=257)
	DW	Communications Signal Analyzer, Tektronix Website (www.tektronix.com/optical)
	DX	RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix Website (www.Tektronix.com/accessories)

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	ED		A New Digital PLL at the Technische Unversitaet Berlin, Technische Unversitaet Berlin Website (www.tdl.com/~gottsch/tuberlin.htm)				
	EE		Low Jitter Digital PLL – ZL30407, Zalink Semiconductor Website, (http://products.zalink.com/product_portlets/new_timer.htm)				
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	EG		Russ Brown, Quantam Corporation, "Eye Diagram Data", SCSI Physical Working Group, February 9, 2000				
	EH		Dave Fink, Tektronix "Introduction to Measurement Techniques and Analysis of Emerging Serial Data Standards", November 2002				
	EI		"Methodologies for Jitter Specification Technical Report" Rev 10, June 9, 1999				
	EJ		Andy Baldman, University of New Hampshire "Description of XAUI Physical Layer Measurements Performed At The UNH Interoperability Lab", October 30, 2002				
	EK		University of New Hampshire Technical Document, "fast Ethernet" February 13, 2003				
	EL		Dennis Derickson, "Fiber Optic Test and Measurement (Chapter 8); Prentice Hall PTR, 1998, pps. 284-338				
	EM		Adam Healey et al., "Fast Ethernet Consortium - 100 Base-TX PMD Test Suite", Version 2.4 and Version 2.5; InterOperability Lab, 1998-1999				
	EN		Adam Healey, "Fast Ethernet Consortium Notebook", 1996-1997 14 pps.				

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